

RETRACTED ARTICLE: Nanocharacterization of Titanium Nitride Thin Films Obtained by Reactive Magnetron Sputtering

VIOLETA VALENTINA MERIE,^{1,3,4} MARIUS SORIN PUSTAN,¹
CORINA BÎRLEANU,¹ and GAVRIL NEGREA²

1.—Department of Mechanical Systems Engineering, Faculty of Machine Building, Technical University of Cluj-Napoca, 103-105 Muncii Avenue, Cluj-Napoca, Romania. 2.—Department of Materials Science and Engineering, Faculty of Materials and Environmental Engineering, Technical University of Cluj-Napoca, 103-105 Muncii Avenue, Cluj-Napoca, Romania. 3.—e-mail: vio1919@yahoo.com. 4.—e-mail: violeta.merie@stm.utcluj.ro

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ELECTRONIC SUPPLEMENTARY MATERIAL

The online version of this article (doi:[10.1007/s11837-015-1460-2](https://doi.org/10.1007/s11837-015-1460-2)) contains supplementary material, which is available to authorized users.